

Day : Tuesday  
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Time: 17:57:00

# PALM INTRANET

## Inventor Name Search Result

Your Search was:

Last Name = HONDA

First Name = TOSHIFUMI

| Application#  | Patent#       | Status | Date Filed | Title   | Inventor Name       |
|---------------|---------------|--------|------------|---|---------------------|
| 08967015      | 6333992<br>✓  | 150    | 11/10/1997 | DEFECT JUDGEMENT<br>PROCESSING METHOD AND<br>APPARATUS  | HONDA,<br>TOSHIFUMI |
| 08968125      | 6249598       | 150    | 11/12/1997 | SOLDER TESTING<br>APPARATUS   | HONDA,<br>TOSHIFUMI |
| 09413468      | 6622054<br>✓  | 150    | 10/06/1999 | METHOD MONITORING A<br>QUALITY OF ELECTRONIC<br>CIRCUITS AND ITS<br>MANUFACTURING<br>CONDITION AND SYSTEM<br>FOR IT | HONDA,<br>TOSHIFUMI |
| 09661182      | 6553323<br>✓  | 150    | 09/13/2000 | METHOD AND ITS<br>APPARATUS FOR<br>INSPECTING A SPECIMEN  | HONDA,<br>TOSHIFUMI |
| 10081782      | 7181060<br>✓  | 150    | 02/20/2002 | DEFECT INSPECTION<br>METHOD   | HONDA,<br>TOSHIFUMI |
| 10224087      | 6965429<br>✓  | 150    | 08/19/2002 | METHOD OF REVIEWING<br>DETECTED DEFECTS   | HONDA,<br>TOSHIFUMI |
| 10256585      | 6855930<br>✓  | 150    | 09/27/2002 | DEFECT INSPECTION<br>APPARATUS AND DEFECT<br>INSPECTION METHOD  | HONDA,<br>TOSHIFUMI |
| 10378016<br>✓ | Not<br>Issued | 71     | 02/28/2003 | Method and its apparatus for<br>classifying defects   | HONDA,<br>TOSHIFUMI |
| 10640343<br>✓ | Not<br>Issued | 71     | 08/12/2003 | Defect inspection method  | HONDA,<br>TOSHIFUMI |
| 10762091<br>✓ | Not<br>Issued | 71     | 01/20/2004 | Method of classifying defects   | HONDA,<br>TOSHIFUMI |
| 10794267<br>✓ | Not<br>Issued | 41     | 03/04/2004 | Defect classification method  | HONDA,<br>TOSHIFUMI |
| 10809464<br>✓ | Not<br>Issued | 61     | 03/26/2004 | Method and its apparatus for<br>classifying defects   | HONDA,<br>TOSHIFUMI |
| 10954421<br>✓ | Not<br>Issued | 71     | 10/01/2004 | Method of observing defects   | HONDA,<br>TOSHIFUMI |

|               |              |     |            |  |                  |
|---------------|--------------|-----|------------|--|------------------|
| 11020255      | 7105815<br>✓ | 150 | 12/27/2004 | METHOD AND APPARATUS FOR COLLECTING DEFECT IMAGES  | HONDA, TOSHIFUMI |
| 11020265      | 7075077<br>✓ | 150 | 12/27/2004 | METHOD OF OBSERVING A SPECIMEN USING A SCANNING ELECTRON MICROSCOPE  | HONDA, TOSHIFUMI |
| 11042021      | 7205555<br>✓ | 150 | 01/24/2005 | DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD   | HONDA, TOSHIFUMI |
| 11130121      | 7361896      | 150 | 05/17/2005 | SCANNING ELECTRON MICROSCOPE AND A METHOD FOR ADJUSTING A FOCAL POINT OF AN ELECTRON BEAM OF SAID SCANNING ELECTRON MICROSCOPE | HONDA, TOSHIFUMI |
| 11190829<br>✓ | Not Issued   | 30  | 07/28/2005 | Method and its apparatus for classifying defects   | HONDA, TOSHIFUMI |
| 11248697      | 7170593<br>✓ | 150 | 10/11/2005 | METHOD OF REVIEWING DETECTED DEFECTS   | HONDA, TOSHIFUMI |
| 11268568<br>✓ | Not Issued   | 41  | 11/08/2005 | Scanning electron microscope and system for inspecting semiconductor device  | HONDA, TOSHIFUMI |
| 11311254<br>✓ | Not Issued   | 30  | 12/20/2005 | Method and apparatus for reviewing defects   | HONDA, TOSHIFUMI |
| 11319721      | Not Issued   | 71  | 12/29/2005 | Scanning electron microscope and method for detecting an image using the same  | HONDA, TOSHIFUMI |
| 11325552<br>✓ | Not Issued   | 30  | 01/05/2006 | Method and apparatus for reviewing defects   | HONDA, TOSHIFUMI |
| 11415286      | Not Issued   | 30  | 05/02/2006 | Observing method and its apparatus using electron microscope   | HONDA, TOSHIFUMI |
| 11488636<br>✓ | Not Issued   | 30  | 07/19/2006 | Method and apparatus for reviewing defects of semiconductor device   | HONDA, TOSHIFUMI |
| 11634963<br>✓ | Not Issued   | 30  | 12/07/2006 | Method and apparatus of reviewing defects on a semiconductor device  | HONDA, TOSHIFUMI |
| 11668510<br>✓ | Not Issued   | 30  | 01/30/2007 | METHOD AND APPARATUS FOR REVIEWING DEFECTS   | HONDA, TOSHIFUMI |
| 11677669<br>✓ | Not Issued   | 30  | 02/22/2007 | METHOD AND APPARATUS FOR DISPLAYING DETECTED DEFECTS   | HONDA, TOSHIFUMI |

|               |               |    |            |  |                     |
|---------------|---------------|----|------------|--|---------------------|
| 11704228<br>✓ | Not<br>Issued | 51 | 02/09/2007 | Method and apparatus for<br>reviewing defects by detecting<br>images having voltage contrast                                       | HONDA,<br>TOSHIFUMI |
| 11704350<br>✓ | Not<br>Issued | 30 | 02/09/2007 | Method and apparatus for<br>reviewing defects  | HONDA,<br>TOSHIFUMI |
| 11747253<br>✓ | Not<br>Issued | 25 | 05/11/2007 | SEM-TYPE REVIEWING<br>APPARATUS AND A METHOD<br>FOR REVIEWING DEFECTS<br>USING THE SAME  | HONDA,<br>TOSHIFUMI |
| 11779937<br>✓ | Not<br>Issued | 30 | 07/19/2007 | REVIEWING APPARATUS<br>USING A SEM AND METHOD<br>FOR REVIEWING DEFECTS<br>OR DETECTING DEFECTS<br>USING THE REVIEWING<br>APPARATUS | HONDA,<br>TOSHIFUMI |
| 12033470<br>✓ | Not<br>Issued | 19 | 01/01/0001 | DEFECT REVIEW METHOD<br>AND DEVICE FOR<br>SEMICONDUCTOR DEVICE   | HONDA,<br>TOSHIFUMI |

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## Inventor Name Search Result

Your Search was:

Last Name = OKUDA

First Name = HIROHITO

| Application#  | Patent#      | Status | Date Filed | Title  | Inventor Name   |
|---------------|--------------|--------|------------|--|-----------------|
| 09413468      | 6622054      | 150    | 10/06/1999 | METHOD MONITORING A QUALITY OF ELECTRONIC CIRCUITS AND ITS MANUFACTURING CONDITION AND SYSTEM FOR IT | OKUDA, HIROHITO |
| 10050519      | 7231079<br>✓ | 150    | 01/18/2002 | METHOD AND SYSTEM FOR INSPECTING ELECTRONIC CIRCUIT PATTERN  | OKUDA, HIROHITO |
| 10081782      | 7181060<br>✓ | 150    | 02/20/2002 | DEFECT INSPECTION METHOD   | OKUDA, HIROHITO |
| 10224087      | 6965429<br>✓ | 150    | 08/19/2002 | METHOD OF REVIEWING DETECTED DEFECTS   | OKUDA, HIROHITO |
| 10256585      | 6855930<br>✓ | 150    | 09/27/2002 | DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD   | OKUDA, HIROHITO |
| 10378016<br>✓ | Not Issued   | 71     | 02/28/2003 | Method and its apparatus for classifying defects   | OKUDA, HIROHITO |
| 10640343<br>✓ | Not Issued   | 71     | 08/12/2003 | Defect inspection method   | OKUDA, HIROHITO |
| 10762091<br>✓ | Not Issued   | 71     | 01/20/2004 | Method of classifying defects  | OKUDA, HIROHITO |
| 10794267<br>✓ | Not Issued   | 41     | 03/04/2004 | Defect classification method   | OKUDA, HIROHITO |
| 10809464<br>✓ | Not Issued   | 61     | 03/26/2004 | Method and its apparatus for classifying defects   | OKUDA, HIROHITO |
| 10918340      | 7034299      | 150    | 08/16/2004 | TRANSMISSION ELECTRON MICROSCOPE SYSTEM AND METHOD OF INSPECTING A SPECIMEN USING THE SAME           | OKUDA, HIROHITO |
| 11020265      | 7075077      | 150    | 12/27/2004 | METHOD OF OBSERVING A SPECIMEN USING A   | OKUDA, HIROHITO |

|               |               |     |            |   |                    |
|---------------|---------------|-----|------------|---|--------------------|
|               |               |     |            | SCANNING ELECTRON<br>MICROSCOPE   |                    |
| 11042021      | 7205555<br>✓  | 150 | 01/24/2005 | DEFECT INSPECTION<br>APPARATUS AND DEFECT<br>INSPECTION METHOD  | OKUDA,<br>HIROHITO |
| 11248697      | 7170593<br>✓  | 150 | 10/11/2005 | METHOD OF REVIEWING<br>DETECTED DEFECTS   | OKUDA,<br>HIROHITO |
| 11478615      | Not<br>Issued | 30  | 07/03/2006 | Apparatus and method for electron<br>beam inspection with projection<br>electron microscopy   | OKUDA,<br>HIROHITO |
| 11488734<br>✓ | Not<br>Issued | 30  | 07/19/2006 | Method and apparatus for<br>inspecting defects of circuit<br>patterns   | OKUDA,<br>HIROHITO |
| 11601723<br>✓ | Not<br>Issued | 30  | 11/20/2006 | Method and apparatus for<br>inspecting pattern defects and<br>mirror electron projection Type or<br>multi-beam scanning type electron<br>beam apparatus | OKUDA,<br>HIROHITO |

Inventor Search Completed: No Records to Display.

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